



Subject card

Subject name and code	Microscopic Methods in Nanotechnology, PG_00069347						
Field of study	Nanotechnology						
Date of commencement of studies	October 2024		Academic year of realisation of subject		2025/2026		
Education level	first-cycle studies		Subject group		Optional subject group Subject group related to scientific research in the field of study		
Mode of study	Full-time studies		Mode of delivery		at the university		
Year of study	2		Language of instruction		Polish		
Semester of study	4		ECTS credits		1.0		
Learning profile	general academic profile		Assessment form		assessment		
Conducting unit	Institute of Nanotechnology and Materials Engineering -> Faculty of Applied Physics and Mathematics -> Wydział Politechniki Gdańskiej						
Name and surname of lecturer (lecturers)	Subject supervisor		dr hab. inż. Jakub Karczewski				
	Teachers		dr hab. inż. Jakub Karczewski				
Lesson types and methods of instruction	Lesson type	Lecture	Tutorial	Laboratory	Project	Seminar	SUM
	Number of study hours	0.0	0.0	15.0	0.0	0.0	15
	E-learning hours included: 0.0						
Learning activity and number of study hours	Learning activity	Participation in didactic classes included in study plan		Participation in consultation hours		Self-study	SUM
	Number of study hours	15		1.0		9.0	25
Subject objectives	Understanding modern methods of imaging nanostructures.						
Learning outcomes	Course outcome		Subject outcome		Method of verification		
	[K6_U04] can plan and conduct experiments, critically analyze their results, draw conclusions and formulate opinions. Has laboratory experience.		The student is able to prepare, perform, and interpret an experiment using modern imaging methods.		[SU4] Assessment of ability to use methods and tools [SU3] Assessment of ability to use knowledge gained from the subject [SU2] Assessment of ability to analyse information		
	[K6_W09] Has knowledge of the structure and operation of scientific instruments, measuring and test equipment and in the field of planning and conducting a physical experiment and critical analysis of its results.		The student knows and understands the principles of operation and is able to perform measurements using SEM, AFM, and STM microscopy.		[SW1] Assessment of factual knowledge		
	[K6_U02] can analyze and solve simple scientific and technical problems based on possessed knowledge, applying analytical, numerical, simulation and experimental methods.		The student is able to prepare samples of nanomaterials for imaging using selected microscopic methods.		[SU4] Assessment of ability to use methods and tools [SU3] Assessment of ability to use knowledge gained from the subject		
Subject contents	Imaging of nanomaterials using tunneling microscopy, atomic force microscopy, and scanning electron microscopy						
Prerequisites and co-requisites	knowledge of basic physics						
Assessment methods and criteria	Subject passing criteria		Passing threshold		Percentage of the final grade		
	presentation of laboratory work results		50.0%		100.0%		
Recommended reading	Basic literature		<ul style="list-style-type: none">Weilie Zhou Zhong Lin Wang "Scanning Microscopy for Nanotechnology Techniques and Applications"V. L.Mironov "Fundamentals of Scanning Probe Microscopy"				
	Supplementary literature		Nanosurf easyScan 2 - operating instruction				

	eResources addresses	
Example issues/ example questions/ tasks being completed	<ul style="list-style-type: none"> • Imaging gold nanoparticles using AFM • Imaging carbon nanotubes using SEM 	
Work placement	Not applicable	

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